

Notice of References Cited	Application/Control No. 10/020,776	Applicant(s)/Patent Under Reexamination FRITSCH ET AL.	
	Examiner ALEX NOGUEROLA	Art Unit 1753	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,773,270	06-1998	D'Orazio et al.	204/403.01
	B	US-5,820,551	10-1998	Hill et al.	204/403.04
	C	US-4,225,410	09-1980	Pace, Salvatore J.	204/412
	D	US-5,437,999	08-1995	Diebold et al.	204/403.11
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP - 03-176657 A	07-1991	JP	Suzuki et al.	G01N 27/30
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wehmeyer et al. ("Electroanalytical Properties of Band Electrodes of Submicrometer Width," Anal. Chem. 1985, 57, 1913-1916)
	V	Thormann et al. ("Voltammetry at Linear Gold and Platinum Microelectrode Arrays Produced by Lithographic techniques," Anal. Chem. 1985, 57, 2764-2770)
	W	Derwent abstract of JP 03-176657 A
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Alex Noguera
6/15/05